

## EAST SEARCH

2/3/2007

L#	Hits	Search String	Databases
S1	494501	(chemical or petrochemical or manufacturing) near2 process\$2	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S2	573	((chemical or petrochemical or manufacturing) near2 process\$2) with (process near2 model\$	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S3	785	((chemical or petrochemical or manufacturing) near2 process\$2) same (process near2 model\$	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S4	785	S2 or S3	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S5	73	S4 and (integrated near2 model\$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S6	5	S4 and (symbolic near2 (model\$3 or language))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S7	85	S4 and (process with environment with model\$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S8	20	S4 and ((log or logging) with (assumption or (model near2 transformation)))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S9	1	S4 and (symbolic near2 (manipulation or representation or description))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S10	1	S4 and ((rate near2 change) with (mass near2 (vapor or liquid)))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S11	2	S4 and (ancestor near2 model\$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S12	52	S4 and (rate near2 change)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S13	10	S4 and (energy near2 (vapor or liquid))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S14	6	S4 and ((pressure or thermal) near2 equilibrium)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S15	4	S4 and ('equal pressure" or "gas law" or "volume correlation")	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S16	207	S9 or S13	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S17	153	S28 and S29	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S18	1	S4 and ((specific or environment) near2 model\$3)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S19	132	S28 or S30	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S20	20	S31 and (S6 or S7)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S21	2	S4 and (formal near2 language)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S22	3	S4 and (model near2 transformation)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S23	9	S31 and S20	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S24	2	S31 and S21	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S25	4	S31 and S27	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S26	33	S4 and ((formal near2 language) or (equation near2 based))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S27	8	S4 and (Mathematica or Axiom or MAPLE or ADIFOR)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S28	35	S4 and (generic near2 (model\$3 or component))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S29	142	S4 and (model\$3 with (assumption or environment))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S30	2	S4 and (component near2 specific near2 model)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S31	65	S4 and (component near2 model)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S32	9	S4 and (environment near2 independent)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S33	75	S4 and (log or logging)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S34	2	S4 and (flash near2 column)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S35	3	S4 and (parameter near2 representation)	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S36	6	S4 and ((vapor or liquid) near2 (enthalpy or heat))	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S37	306	S5 or S6 or S7 or S8 or S10 or S11 or S12 or S14 or S15 or S16 or S17 or S19 or S20 or S21	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S38	3	S31 and S34	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S39	8	S31 and S11	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB
S40	85	S31 and S17	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB

S39	7	S31 and S38	US_PGPUB; USPAT; USOCR; FPRs; EPO; JPO; DERWENT; IBM_TDB
S42	3	S4 and (mass near2 (vapor or liquid))	US_PGPUB; USPAT; USOCR; FPRs; EPO; JPO; DERWENT; IBM_TDB
S44	6	S31 and S25	US_PGPUB; USPAT; USOCR; FPRs; EPO; JPO; DERWENT; IBM_TDB
S43	10	S31 and (S24 or S42)	US_PGPUB; USPAT; USOCR; FPRs; EPO; JPO; DERWENT; IBM_TDB
S46	573	((chemical or petrochemical or manufacturing) near2 process\$2) with (process near2 model\$	US_PGPUB; USPAT; USOCR; FPRs; EPO; JPO; DERWENT; IBM_TDB
S48	785	S46 or S47	US_PGPUB; USPAT; USOCR; FPRs; EPO; JPO; DERWENT; IBM_TDB
S49	73	S48 and (integrated near2 model\$3)	US_PGPUB; USPAT; USOCR; FPRs; EPO; JPO; DERWENT; IBM_TDB
S51	20	S48 and (symbolic near2 (manipulation or representation or description))	US_PGPUB; USPAT; USOCR; FPRs; EPO; JPO; DERWENT; IBM_TDB
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S58	2	S48 and (component near2 specific near2 mode)	US_PGPUB; USPAT; USOCR; FPRs; EPO; JPO; DERWENT; IBM_TDB
S52	2	S48 and (ancestor near2 model\$3)	US_PGPUB; USPAT; USOCR; FPRs; EPO; JPO; DERWENT; IBM_TDB
S59	65	S48 and (component near2 mode)	US_PGPUB; USPAT; USOCR; FPRs; EPO; JPO; DERWENT; IBM_TDB
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S71	306	S49 or S50 or S51 or S52 or S54 or S55 or S56 or S58 or S59 or S60 or S61 or S62 or S63 c	US_PGPUB; USPAT; USOCR; FPRs; EPO; JPO; DERWENT; IBM_TDB
S72	207	S53 or S57	US_PGPUB; USPAT; USOCR; FPRs; EPO; JPO; DERWENT; IBM_TDB
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S65	1	S48 and ((rate near2 change) with (mass near2 (vapor or liquid)))	US_PGPUB; USPAT; USOCR; FPRs; EPO; JPO; DERWENT; IBM_TDB
S66	52	S48 and (rate near2 change)	US_PGPUB; USPAT; USOCR; FPRs; EPO; JPO; DERWENT; IBM_TDB
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S69	6	S48 and ((vapor or liquid) near2 (enthalpy or heat))	US_PGPUB; USPAT; USOCR; FPRs; EPO; JPO; DERWENT; IBM_TDB
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10758630	Vipin Gopal et al.	<b>EAST SEARCH</b>	2/3/2007

**Results of search set S91:**

**Document Kind Code Title**

US 20060195213 A1	Method of operating an advanced process controller by dynamically adapting hierarchy levels	Issue Date 20060831 700/108	Current OR	Abstract
US 20060190913 A1	Method and apparatus for identifying a manufacturing problem area in a layout using a gradient	20060824 716/19		
US 20060190223 A1	SAMPLE PROBABILITY OF FAULT FUNCTION DETERMINATION USING CRITICAL DEFECT SIZE	20060824 703/2		
US 20060190222 A1	PROBABILITY OF FAULT FUNCTION DETERMINATION USING CRITICAL DEFECT SIZE	20060824 703/2		
US 20060178528 A1	Method of controlling acetic acid process	20060810 562/519		
US 20060172427 A1	Method and apparatus for retrofitting existing real time control systems for monitoring, control	20060803 436/55		

US 20060150129 A1	Stochastic analysis process optimization for integrated circuit design and manufacture	20060706 716/4
US 20060136138 A1	Creation and maintenance of a history list in a method and apparatus for integrated modeling	20060622 702/19
US 20060124156 A1	Carbon dioxide snow apparatus	20060615 134/99.1
US 20060117654 A1	Bench scale apparatus to model and develop biopharmaceutical cleaning procedures	20060608 47758.1SC
US 20060111804 A1	System and method for interactive visual representation of information content and relationsh	20060601 707/104.1
US 20060106757 A1	Multivariate control of semiconductor processes	20060525 700/110
US 20060106485 A1	Search for similar sheet metal part models	20060518 707/2
US 20060103378 A1	Enhanced digital process design methodology for process centric CAD systems	20060518 700/182
US 20060101370 A1	Apparatus and method for dynamic diagnostic testing of integrated circuits	20060518 324/228
US 20060100873 A1	METHOD FOR IMPROVING OPTICAL PROXIMITY CORRECTION	20060511 716/19
US 20060074603 A1	CIRCUIT STATISTICAL MODELING FOR PARTIALLY CORRELATED MODEL PARAMETER	20060511 704/256.2
US 20060074599 A1	Customer support system and method of customer support	20060406 702/188
US 20060074598 A1	Application of abnormal event detection technology to olefins recovery trains	20060406 702/185
US 20060073013 A1	Application of abnormal event detection technology to hydrocracking units	20060406 702/185
US 20060069858 A1	Defect location identification for microdevice manufacturing and test	20060406 416/35
US 20060069541 A1	Reuse of manufacturing process design models as part of a diagnostic system	20060330 714/33
US 20060058898 A1	System and method for abnormal event detection in the operation of continuous industrial prc	20060330 703/22
US 20060015294 A1	Data collection and analysis system	20060316 700/29
US 20050267723 A1	Process for low temperature, dry etching, and dry planarization of copper	20060119 702/183
US 20050272640 A1	Method and apparatus for glucose control and insulin dosing for diabetics	20060119 438/710
US 20050270199 A1	Method for designing mixed signal integrated circuits and configurable synchronous digital nc	20051208 514/3
US 20050268256 A1	Modeling resolution enhancement processes in integrated circuit fabrication	20051208 341/120
US 20050261888 A1	Physicochemical process modelling system	20051201 716/4
US 20050261887 A1	Time dependent process parameters for integrated process and product engineering	20051201 703/11
US 20050261791 A1	Time dependent process parameters and engineering change number conflict report	20051201 703/22
US 20050235246 A1	Interfaces from external systems to time dependent process parameters in integrated process	20051201 703/22
US 20050234586 A1	Use of models in integrated circuit fabrication	20051201 716/21
US 20050228511 A1	Predictive modeling of machining line variation	20051020 700/159
US 20050209834 A1	Computer-implemented system and method for measuring and improving manufacturing proc	20051013 700/28
US 20050187747 A1	Horizontally structured CAD/CAM modeling-vertical to horizontal conversion	20051012 703/2
US 20050187746 A1	Method and apparatus for improved simulation of chemical and biochemical reactions	20050825 703/11
US 20050187744 A1	Method and apparatus for improved modeling of chemical and biochemical reactions	20050825 703/11
US 20050187745 A1	Method and apparatus facilitating communication with a simulation environment	20050825 703/11
US 20050187717 A1	Method and apparatus for integrated modeling, simulation and analysis of chemical and biot	20050825 703/11
US 20050187643 A1	Parametric universal nonlinear dynamics approximator and use	20050825 702/19
US 20050181342 A1	Medical training simulator including contact-less sensors	20050825 700/29
US 20050159934 A1	Integrated modeling through symbolic manipulation	20050818 434/262
US 20050154477 A1	Kiln control and upset recovery using a model predictive control in series with forward chainin	20050721 703/2
US 20050132306 A1	Characterization and reduction of variation for integrated circuits	20050714 700/37
US 20050120010 A1	System and method for determining costs within an enterprise	20050616 716/1
US 20050065767 A1	Closed loop integration of digital models of <i>in silico</i> systems and experimental procedures	20050602 707/3
US 20050065626 A1	Material reservation distribution system and method	20050324 703/22
US 20050060584 A1	Trusted infrastructure support systems, methods and techniques for secure electronic comm	20050324 700/97
US 20050045029 A1	Selective separation of fluid compounds utilizing a membrane separation process	20050317 726/4
US 20050037522 A1	Dummy fill for integrated circuits	20050303 95/46
US 20050010319 A1	System and method for validating and visualizing APC assisted semiconductor manufacturing	20050217 438/8
US 20050004687 A1	Apparatus and method of controlling multi-input-single-output systems	20050113 700/121
		20050106 700/44

US 20040256230 A1	Microfluidic devices for transverse electrophoresis and isoelectric focusing	2004/12/23 204/450
US 20040230411 A1	Apparatus and methods for predicting properties of processed material	2004/11/18 703/6
US 20040220691 A1	Method and apparatus for constructing crowns, bridges and implants for dental use	2004/11/04 700/98
US 20040220689 A1	Sensor placement and control design for distributed parameter systems	2004/11/04 700/97
US 20040182786 A1	Purification of fluid compounds utilizing a distillation - membrane separation process	2004/10/21 703/9
US 20040167763 A1	Information processing method for evaluating biochemical pathway models using clinical data	2004/08/23 210/640
US 20040154965 A1	Wet and dry weather water flows disinfection system	2004/08/12 210/85
US 20040153296 A1	Horizontally structured CAD/CAM coordinate system	2004/08/05 703/2
US 20040153202 A1	Horizontally structured manufacturing process modeling: across file feature operability	2004/08/05 700/182
US 20040153201 A1	Horizontally structured CAD/CAM coordinate system for manufacturing design	2004/08/05 700/182
US 20040153200 A1	Horizontally structured manufacturing process modeling: exterior linked representational emb	2004/08/05 700/182
US 20040153197 A1	Modeling an abrasive process to achieve controlled material removal	2004/08/05 700/164
US 20040148047 A1	Hierarchical methodology for productivity measurement and improvement of productions syst	2004/07/29 700/100
US 20040139419 A1	Minimization of microelectronic interconnect thickness variations	2004/07/15 716/20
US 20040130276 A1	System and method of applying adaptive control to the control of particle accelerators with va	2004/07/08 315/501
US 20040128003 A1	SYSTEM AND METHOD FOR MODEL BASED CONTROL OF A NEURAL NETWORK	2004/07/01 700/31
US 20040128002 A1	SYSTEM AND METHOD FOR MODEL BASED CONTROL OF A CHEMICAL PROCESS	2004/07/01 700/31
US 20040123129 A1	Trusted infrastructure support systems, methods and techniques for secure electronic commerce	2004/06/24 713/193
US 20040121495 A1	Dynamic adaptive sampling rate for model prediction	2004/06/24 438/14
US 20040117040 A1	System and method of adaptive control of processes with varying dynamics	2004/06/17 700/29
US 20040102935 A1	Method for regulating a property of a product derived from a chemical transformation	2004/05/27 118/715
US 20040099213 A1	Spatially programmable microelectronics process equipment using segmented gas injection s	2004/05/13 700/108
US 20040093107 A1	Probability constrained optimization for electrical fabrication control	2004/05/13 700/108
US 20040088149 A1	Method and apparatus for performing OPC using model curvature	2004/05/06 703/13
US 20040085065 A1	Cooperative smart items	2004/05/06 700/95
US 20040083452 A1	Method and system for predicting multi-variable outcomes	2004/04/29 717/109
US 20040083028 A1	Process control using on-line instrumentation and process models	2004/04/29 700/269
US 20040076944 A1	Supervised learning in the presence of null data	2004/04/22 434/433
US 20040068332 A1	Method of designing and manufacturing rubber process tooling using an interface to a CAD/C	2004/04/08 700/182
US 20040034555 A1	Stochastic modeling of spatial distributed sequences	2004/04/08 700/51
US 20040034517 A1	Hierarchical methodology for productivity measurement and improvement of complex product	2004/04/08 700/51
US 20040028253 A1	DEVICE MODELING FOR PROXIMITY EFFECTS	2004/02/19 705/7
US 20040028253 A1	Detoxification of solid freeform fabrication materials	2004/02/19 703/14
US 20040015335 A1	Method, system and medium for controlling manufacturing process using adaptive models ba	2004/02/12 381/322
US 20030237064 A1	Characterization and verification for integrated circuit designs	2004/01/22 703/2
US 20030229881 A1	Adjustment of masks for integrated circuit fabrication	2003/12/11 716/19
US 20030229880 A1	Test masks for lithographic and etch processes	2003/12/11 716/19
US 20030229875 A1	Use of models in integrated circuit fabrication	2003/12/11 716/10
US 20030229868 A1	Electronic design for integrated circuits based process related variations	2003/12/11 716/5
US 200302298412 A1	Electronic design for integrated circuits based on process related variations	2003/12/11 700/121
US 200302298410 A1	Integrated circuit metrology	2003/12/11 700/109
US 20030200064 A1	One-dimensional modeling of the manufacture of multi-layered material	2003/10/23 703/2
US 20030195708 A1	Method for analyzing an unknown material as a blend of known materials calculated so as to	2003/10/16 702/22
US 20030149502 A1	Method and system for creating a tooling master model for manufacturing parts	2003/08/07 700/98
US 20030143498 A1	Method and system for reverse and re-engineering parts	2003/08/07 700/97
US 20030146761 A1	Apparatus and method for dynamic diagnostic testing of integrated circuits	2003/08/07 324/501
US 20030144758 A1	System and method for integrating geometric models	2003/07/31 700/104

US 20030136201 A1	Patient monitoring system employing array of force sensors on a bedsheet or similar substrati	20030724 73/862.41
US 20030120372 A1	System, method and computer program product for mapping data of multi-database origins	20030626 700/108
US 20030115005 A1	System and method for controlling critical dimension in a semiconductor manufacturing proce	20030619 702/184
US 20030114950 A1	System, method and computer program product for mapping data of multi-database origins	20030619 700/108
US 20030098292 A1	Reusable software components for invoking computational models	20030529 700/121
US 20030097243 A1	Process for low temperature, dry etching, and dry planarization of copper	20030529 216/78
US 20030097197 A1	Method and system for operating a hydrocarbon production facility	20030522 703/2
US 20030093762 A1	Method, system and storage medium for enhancing process control	20030522 700/108
US 20030074174 A1	Large scale process control by driving factor identification	20030515 716/2
US 20030061015 A1	Manufacturing methods and systems for rapid production of hearing-aid shells	20030417 703/13
US 20030046130 A1	System and method for real-time enterprise optimization	20030327 703/2
US 20030033041 A1	System and method for producing an assembly by directly implementing three-dimensional cx	20030306 705/7
US 20030028265 A1	Klin/cooler control and upset recovery using a combination of model predictive control and ex	20030213 700/98
US 200300232403 A1	Process for estimating random error in chemical and biological assays when random error dif	20030206 700/31
US 200300223386 A1	Metabolome profiling methods using chromatographic and spectroscopic data in pattern reco	20030130 702/179
US 20030005747 A1	Method for detecting and correcting sensor failure in oil and gas production system	20030130 702/19
US 20030004596 A1	Horizontally-structured CAD/CAM modeling for virtual concurrent product and process design	20030109 73/1.16
US 20020199123 A1	Security architecture for a process control platform executing applications	20030102 700/98
US 20020198920 A1	Supervisory process control and manufacturing information system application having a layer	20021226 726/3
US 20020198897 A1	Universal epistemological machine (a.k.a. android)	20021226 718/100
US 20020198616 A1	Manufacturing scheduling process with improved modeling, scheduling and editing capabilities	20021226 700/99
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US 20020171176 A1	Detoxification of solid freeform fabrication materials	20021121 264/401
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US 20020156542 A1	Methods, devices and systems for monitoring, controlling and optimizing processes	20021024 700/30
US 20020152000 A1	Automated horizontally structured manufacturing process design modeling	20021017 700/98
US 20020136822 A1	Method and apparatus for monitoring the coating on particle during manufacturing of a pharm	20020926 427/8
US 20020133803 A1	Enhancement to horizontally-structured CAD/CAM modeling	20020919 717/104
US 20020133267 A1	Enhancement to horizontally structured manufacturing process modeling for alternate operations, large parts &	20020919 700/182
US 20020133266 A1	Horizontally structured manufacturing process modeling for concurrent product and process c	20020919 700/182
US 20020133265 A1	Horizontally structured manufacturing process modeling for virtual fixture and tooling processes	20020919 700/182
US 20020133253 A1	Horizontally-structured CAD/CAM modeling for virtual fixture and tooling	20020919 700/98
US 20020133252 A1	Horizontally-structured manufacturing process modeling for fixtures and tooling	20020919 700/98
US 20020117782 A1	Method for simulating chemical reactions	20020919 700/97
US 20020103548 A1	Computer method and apparatus for optimized controller in a non-linear process	20020815 703/12
US 20020077719 A1	Variable parameter controls for semiconductor processes	20020620 700/117
US 20020072872 A1	Method for diagnosing process parameter variations from measurements in analog circuits	20020613 702/117
US 20020072828 A1	Computer method and apparatus for constraining a non-linear approximator of an empirical p	20020613 700/269
US 20020055903 A1	System, method and computer program product for mapping data of multi-database origins	20020516 700/19
US 20020052858 A1	Method and tool for data mining in automatic decision making systems	20020502 706/15
US 20020038163 A1	Apparatus and method for managing and distributing design and manufacturing information <sup>1</sup>	20020328 700/165
US 20010025232 A1	Hybrid linear-neural network process control	20010927 703/13
US 20010020395 A1	Patient monitoring system employing array of force sensors on a bedsheet or similar substrat	20010913 73/862.041
US 77110956 B1	Capability predictor	20060919 705/7
US 7110849 B2	Horizontally-structured CAD/CAM modeling for virtual fixture and tooling processes	20060919 700/159
US 7106897 B1	Universal spatial pattern recognition system	20060912 382/145

US 7099804 B2	Automated horizontally structured manufacturing process design modeling	20060829 703/1
US 7089081 B2	Modeling an abrasive process to achieve controlled material removal	20060808 700/175
US 7089075 B2	Systems and methods for metrology recipe and model generation	20060808 700/121
US 7079908 B2	Horizontally-structured modeling for analysis	20060718 700/98
US 7070694 B2	Purification of fluid compounds utilizing a distillation - membrane separation process	20060704 210/640
US 7064076 B2	Process for low temperature, dry etching, and dry planarization of copper	20060620 438/714
US 7039475 B2	System and method of adaptive control of processes with varying dynamics	20060502 700/31
US 7037172 B1	Advanced water planarizing	20060502 45/15
US 7031782 B2	Material reservation distribution system and method	20060418 700/95
US 7008300 B1	Advanced water refining	20060307 45/141
US 7006889 B2	Sensor placement and control design for distributed parameter systems	20060228 700/204
US 6996245 B2	Detoxification of solid freeform fabrication materials	20060207 38/1322
US 6986802 B2	Selective separation of fluid compounds utilizing a membrane separation process	20060117 95/46
US 6986698 B1	Wafer refining	20060117 45/15
US 6985793 B2	Horizontally structured CAD/CAM coordinate system for manufacturing design	20060110 700/182
US 6975915 B2	Cooperative smart items	20051213 700/108
US 6970757 B1	Method and apparatus for updating control state variables of a process control model based on automated system for extracting and combining tool trace data and wafer electrical test (WET)	20051129 700/108
US 6966303 B1	Dynamic offset and feedback threshold	20051122 703/13
US 6961626 B1	Method and apparatus for monitoring the coating on particle during manufacturing of a pharm	20051101 700/31
US 6959224 B2	Probability constrained optimization for electrical fabrication control	20051025 700/97
US 6955688 B1	Knowledge-engineering protocol-suite	20051004 706/45
US 6950719 B2	Horizontally structured manufacturing process modeling: across file feature operability	20050927 700/182
US 6947883 B1	Method for designing mixed signal integrated circuits and configurable synchronous digital nc	20050920 703/23
US 6946157 B2	System and method for producing an assembly by directly implementing three-dimensional ca	20050920 42/72.15
US 6922599 B2	Method, system and storage medium for enhancing process control	20050726 700/98
US 6915172 B2	Large scale process control by driving factor identification	20050705 700/31
US 6904328 B2	Large area pattern erosion simulator	20050607 700/97
US 6889177 B1	Minimization of microelectronic interconnect thickness variations	20050503 703/2
US 6883153 B2	Forecast test-out of probed fabrication by using dispatching simulation method	20050419 716/6
US 6876894 B1	Apparatus and method for dynamic diagnostic testing of integrated circuits	20050405 700/100
US 6859031 B2	Resin transfer molding	20050222 324/233
US 6846842 B2	Method and system for creating a tooling master model for manufacturing parts	20050215 700/197
US 6840117 B2	Method monitoring system employing array of force sensors on a bedsheet or similar substrat	20050215 700/31
US 6839606 B2	Horizontally structured manufacturing process modeling for fixtures and tooling	20050111 73/862.041
US 6839599 B2	Kin/cooler control and upset recovery using a combination of model predictive control and ex	20050104 700/159
US 6821910 B2	Spatially programmable microelectronics process equipment using segmented gas injection &	20050104 700/79
US 6807583 B2	Method of determining causal connections between events recorded during process executio	20041123 438/758
US 6804568 B1	3-D CAD/CAM data transfer method, 3-D CAD apparatus, 3-D CAM apparatus, 3-D CAD/CAM	20041019 719/318
US 6802045 B1	Method and apparatus for incorporating control simulation environment	20041005 716/2
US 6775585 B2	Method and designing and manufacturing rubber process tooling using an interface to a CAD	20040810 700/182
US 6775581 B2	Horizontally-structured CAD/CAM modeling for virtual concurrent product and process design	20040810 700/98
US 6772082 B2	Method for detecting and correcting sensor failure in oil and gas production system	20040803 702/116
US 6772044 B1	Sensor placement and control design for distributed parameter systems	20040803 700/204
US 6763277 B1	Method and apparatus for proactive dispatch system to improve line balancing	20040713 700/100
US 6757579 B1	Kalman filter state estimation for a manufacturing system	20040629 700/108
US 6754556 B1	Horizontally structured manufacturing process modeling: enhancement to multiple master pro	20040622 700/182
US 6741998 B2	System, method and computer program for mapping a hierarchical display of process data of	20040525 707/102

US 6738682 B1	Method and apparatus for scheduling based on state estimation uncertainties	20040518 700/100
US 6735489 B1	Horizontally structured manufacturing process modeling	20040511 700/95
US 6725230 B2	System, method and computer program for assembling process data of multi-database origin	20040420 707/102
US 6719615 B1	Versatile wafer refining	20040413 45/141
US 6708073 B1	Lot specific process design methodology	20040316 700/121
US 6691127 B1	Storage and retrieval of process capability and guidance information, and computer media therefor	20040210 707/102
US 6699754 B1	Method for optimizing the layout and operation of a reduction method	20031230 75/375
US 6682116 B2	Method for analyzing an unknown material as a blend of known materials calculated so as to detoxify or solid freeform fabrication materials	20031209 702/22
US 6660208 B2	Trusted infrastructure support system, methods and techniques for secure electronic commerce	20031209 264/401
US 6658568 B1	Computer method and apparatus for optimized controller in a non-linear process	20031202 713/193
US 6643616 B1	Integrated device structure prediction based on model curvature	20031125 700/31
US 6643615 B1	Product design process with included producibility information	20031104 703/13
US 6643596 B2	System and method for controlling critical dimension in a semiconductor manufacturing process	20031104 702/84
US 6631630 B1	Hydroforming of composite materials	20031014 72/60
US 6625785 B2	Method for diagnosing process parameter variations from measurements in analog circuits	20030923 716/4
US 6600568 B1	Deriving statistical device models from electrical test data	20030506 703/2
US 6560503 B1	Method and apparatus for monitoring controller performance using statistical process control	20030506 700/108
US 6556959 B1	Method and apparatus for updating a manufacturing model based upon fault data relating to manufacturing process	20030429 703/2
US 6556884 B1	Method and apparatus for interfacing a statistical process control system with a manufacturing process transducing assembly	20030429 700/121
US 6549631 B1	Patient monitoring system employing array of force sensors on a bedsheet or similar substrate	20030415 38/111
US 6546813 B2	Method and apparatus for creating adaptive workflows	20030415 73/862,041
US 6546364 B1	Method for chemical addition utilizing adaptive optimization	20030408 703/22
US 6535795 B1	System and method for classifying an anomaly	20030318 700/266
US 6483938 B1	Designing and making an article of manufacture	20021119 382/149
US 6434441 B1	Auto correction of error checked simulated printed images	20020813 700/98
US 6425112 B1	Manufacturing scheduling process with improved modeling, scheduling and editing capabilities	20020723 716/5
US 6415196 B1	Apparatus and method for managing and distributing design and manufacturing information to a manufacturing process	20020702 700/100
US 6411862 B1	Statistical process window design methodology	20020625 700/182
US 6366822 B1	Method and apparatus for designing a manufacturing process for sheet metal parts	20020402 700/31
US 6356861 B1	Deriving statistical device models from worst-case files	20020312 703/2
US 6353768 B1	Manufacturing process modeling techniques	20020305 700/97
US 6347256 B1	Apparatus and method for automatically diagnosing a technical system with efficient storage	20020212 700/100
US 6343261 B1	Universal machine translator of arbitrary languages	20020129 702/183
US 6341372 B1	Apparatus and method for managing and distributing design and manufacturing information to a manufacturing process	20020122 717/136
US 6327514 B1	Method and apparatus for order promising	20011204 700/145
US 6321133 B1	Method for efficient manufacturing of integrated circuits	20011120 700/100
US 6298470 B1	Method and system for identifying defects in a semiconductor	20011002 716/4
US 6292582 B1	Dynamic creation of workflows from deterministic models of real world processes	20010918 382/149
US 6279009 B1	Hybrid linear-neural network process control	20010821 707/103R
US 6278962 B1	Methods for creating aggregate plans useful in manufacturing environments	20010821 703/13
US 6278901 B1	System and method for designing integrated circuits	20010821 700/99
US 6269277 B1	Computer-implemented value management tool for an asset intensive manufacturer	20010731 700/97
US 6266655 B1	Advanced process control for semiconductor manufacturing	20010724 705/400
US 6263255 B1	Solder testing apparatus	20010717 700/121
US 6249598 B1	System and method for knowledgebase generation and management	20010619 382/150
US 6233545 B1	Universal machine translator of arbitrary languages utilizing epistemic moments	20010612 382/141
		20010515 704/2

US 6219586 B1	Apparatus and method for managing and distributing design and manufacturing information ti	20010417 700/182
US 62122441 B1	Apparatus and method for managing and distributing design and manufacturing information ti	20010403 700/98
US 6205239 B1	System and method for circuit repair	20010320 382/149
US 6202043 B1	Computer based system for imaging and analyzing a process system and indicating values of	20010313 703/17
US 6198980 B1	System and method for designing a mixed-model manufacturing process	20010306 700/99
US 6192329 B1	Method and apparatus for assessing risks of injury	20010220 703/6
US 6185476 B1	Apparatus and method for managing and distributing design and manufacturing information ti	20010206 700/182
US 6173246 B1	Method and system for a unified process automation software system	20010109 703/22
US 6128586 A	Method and device for controlling a self-regulating, delayed process	20001003 702/127
US 6119125 A	Software components for a building automation system based on a standard object superclas	20000912 707/103R
US 6091846 A	Method and system for anomaly detection	20000718 382/145
US 6076048 A	System and method for least squares filtering based leak flow estimation/detection using exp	20000613 702/51
US 6065857 A	Computer readable medium for managing and distributing design and manufacturing informa	20000523 700/95
US 6041263 A	Method and apparatus for simulating and optimizing a plant model	20000321 700/32
US 6014637 A	Object oriented framework mechanism for fulfillment requirements management	20000111 705/26
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US 5978751 A	Variegated manufacturing process test method and apparatus	19991102 702/179
US 5971589 A	Apparatus and method for managing and manufacturing information ti	19991026 700/145
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US 5877954 A	Hybrid linear-neural network process control	19990302 700/29
US 5864482 A	Apparatus and method for managing, distributing design and manufacturing information throu	19990126 700/95
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US 5841660 A	Method and apparatus for modeling process control	19981124 700/115
US 5828867 A	Method for discrete digital event simulation	19981027 703/6
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US 5625552 A	Closed loop neural network automatic tuner	19970429 700/42
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US 5604892 A	Method for modeling a physical system of elements using a relational database	19970218 703/18
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US 5560194 A	Method for optimally controlling fiber processing machines	19961001 572/64
US 5539652 A	Method for manufacturing test simulation in electronic circuit design	19960723 703/14
US 5504692 A	System and method for improved flow data reconciliation	19960402 700/266
US 5481475 A	Method of semiconductor device representation for fast and inexpensive simulations of semic	19960102 716/20
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US 3725653 A	APPARATUS FOR CONTROLLING CHEMICAL PROCESSES	19730403 700/29
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EP 1643399 A	Horizontally structured computer-aided design/computer-aided manufacture (CAD/CAM) man	20060405
US 20060069541 A	Diagnostic method for actual process in manufacturing environment, involves determining diff	20060330
US 20050187745 A	Modeling, simulation, and analysis system for modifying model of biological process responsi	20050825
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